

### Product Description

The Nxbeam NPA1000-DE is a Ku-band high power GaN MMIC fabricated in 0.2um GaN HEMT on SiC. This part is ideally suited for satellite communications, point-to-point radios, and radar applications. The MMIC operates from 12.5 to 15.5 GHz and provides 20 W of saturated output power and 15 W of linear power in an ultra-small footprint of 9.2 mm<sup>2</sup> (4.6 mm x 2.0 mm).



The NPA1000-DE comes in die form with RF input and output matched to 50 Ω with DC blocking capacitors for easy system integration. The HEMT devices are fully passivated for reliable operation. Bond pad and backside metallization are Au-based for compatibility with eutectic die attachment methods.

### Key Features

- Frequency: 12.5– 15.5 GHz
- Linear Gain: 26 dB
- Psat: >43 dBm
- Linear Power: 41.7 dBm at -25 dBc
- PAE: >25%
- Chip Dimensions: 4.6 x 2.0 x 0.1 mm

### Electrical Specifications

Test Condition: Vd = 28V, Idq = 2.0 A, Temp. = 25 °C (all data is CW in-fixture)

Parameter	Min	Typical	Max	Unit
Frequency	12.5		15.5	GHz
Gain (small signal)		26		dB
Output Power (Pin = 21 dBm)		> 43		dBm
Power Gain (Pin = 21 dBm)		> 22		dB
Power Added Efficiency (Pin = 21 dBm)		> 25		%
Input Return Loss		> 12		dB
Output Return Loss		> 9		dB

### Electrical Specifications (Linear Power Operation)

Test Condition: Vd = 26V, Idq = 0.88 A, Temp. = 25 °C

Measured at -25 dBc under QPSK modulation, Channel BW = 1 MHz

Parameter	Min	Typical	Max	Unit
Frequency	12.5		15.5	GHz
Small Signal Gain		22		dB
Linear Output Power		41.7		dBm
Power Gain		20		dB
Power Added Efficiency		22		%

### Absolute Maximum Ratings (Temp. = 25°C)

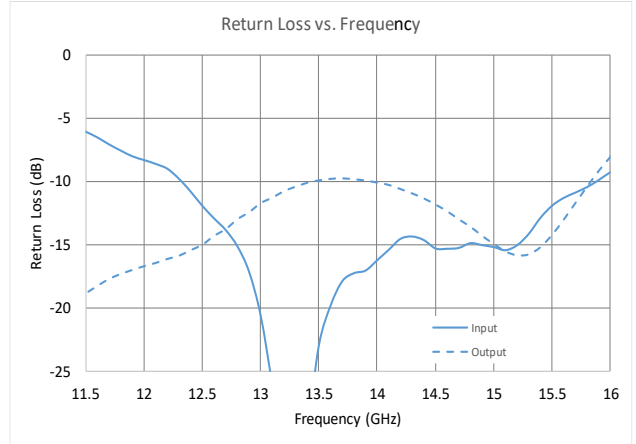
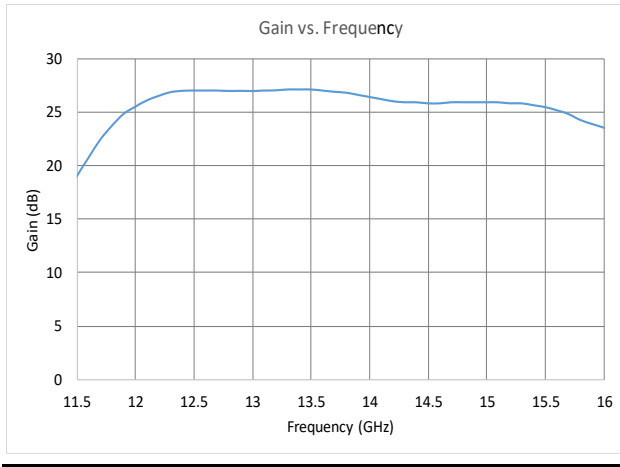
Parameter	Min	Max	Unit
Drain Voltage (Vd1, Vd2, Vd3)		28	V
Drain Current (Id1)		300	mA
Drain Current (Id2)		1050	mA
Drain Current (Id3)		2700	mA
Gate Voltage (Vg1, Vg2, Vg3)	-7	0	V
Input Power (Pin)		TBD	dBm
Assembly Temperature (30 seconds)		320	°C

### Recommended Operating Condition

Parameter	Value	Unit
Drain Voltage (Vd)	20 - 28	V
Drain Current (Idq)	up to 2	A
Gate Voltage (Vg) (Typical)	-3.8	V

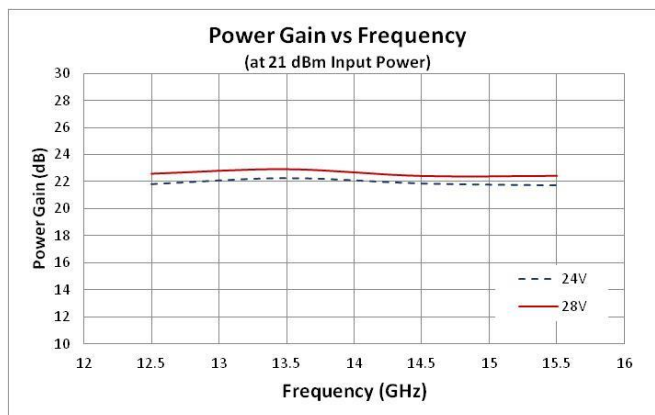
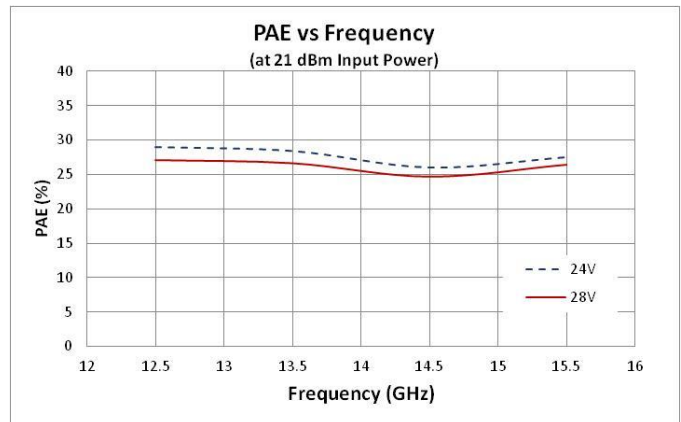
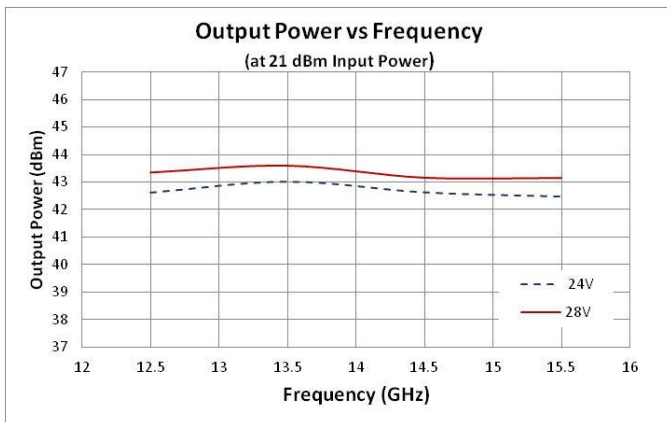
### Small Signal Performance

Test Condition:  $V_d = 28\text{ V}$ ,  $I_{dq} = 1.8\text{ A}$ ,  $Temp. = 25\text{ }^\circ\text{C}$ , (all data is CW in-fixture)



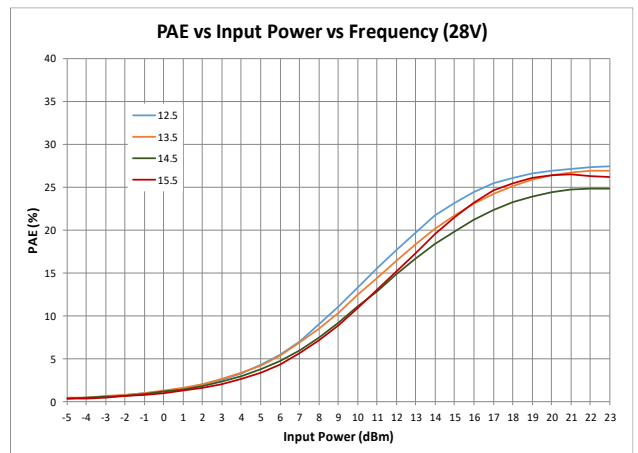
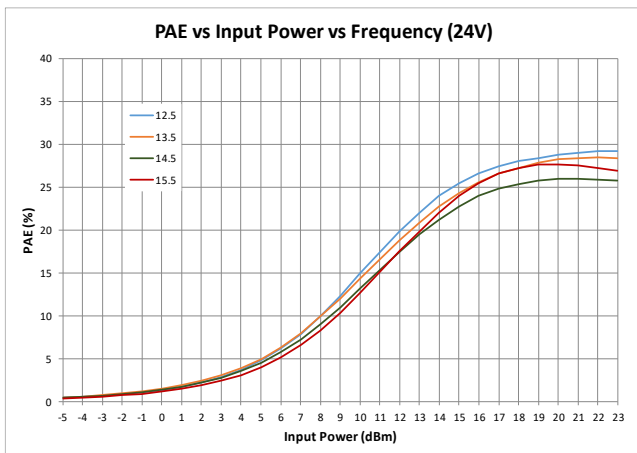
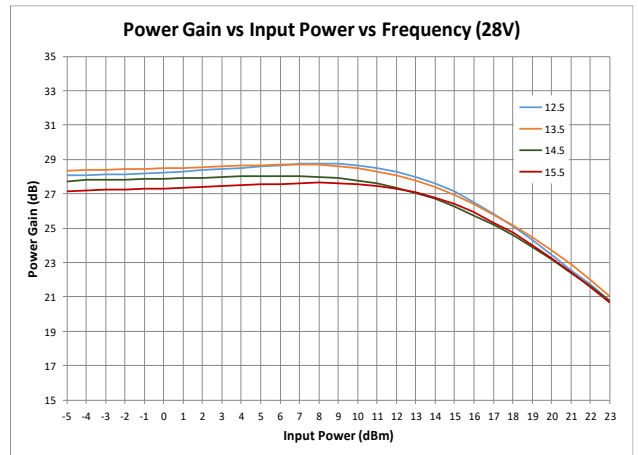
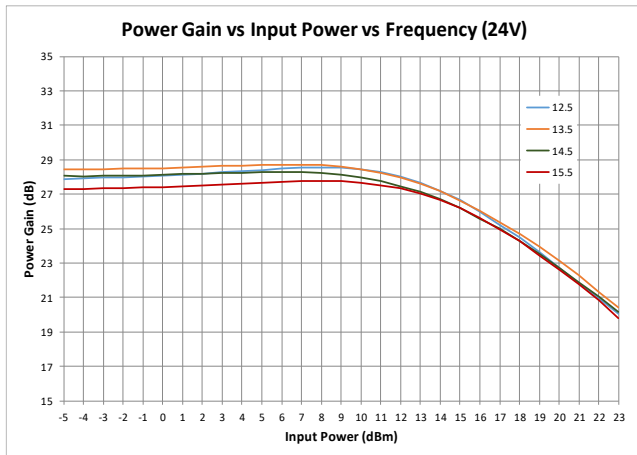
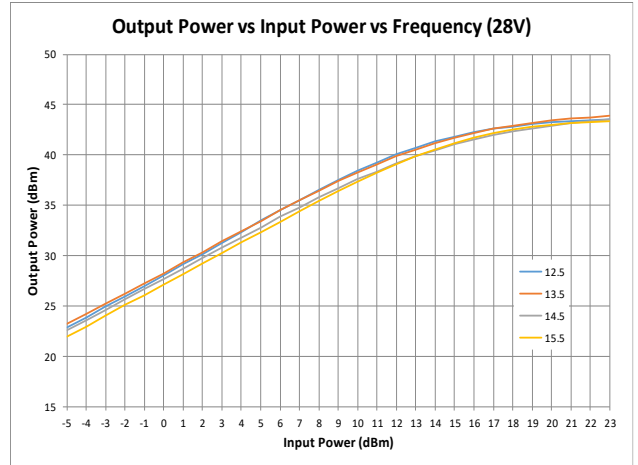
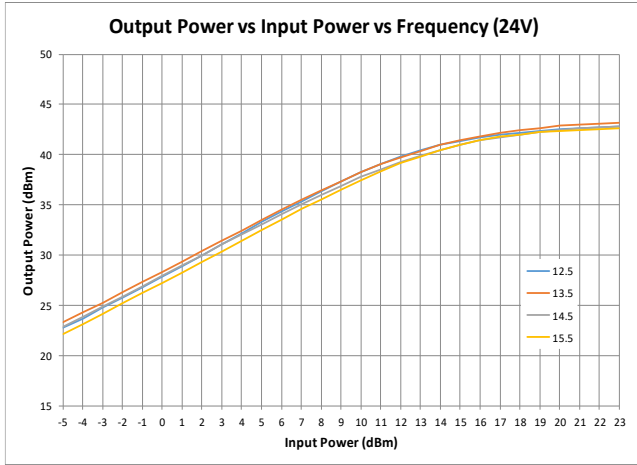
### Large Signal Performance

Test Condition:  $V_d = 28, 24\text{ V}$ ,  $I_{dq} = 2\text{ A}$ ,  $Temp. = 25\text{ }^\circ\text{C}$ , (all data is CW in-fixture)



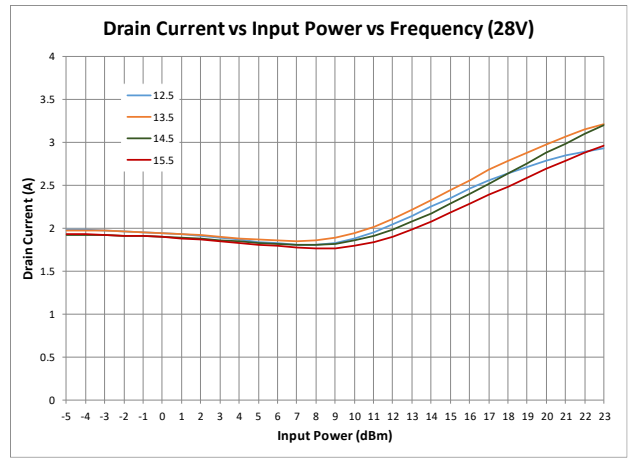
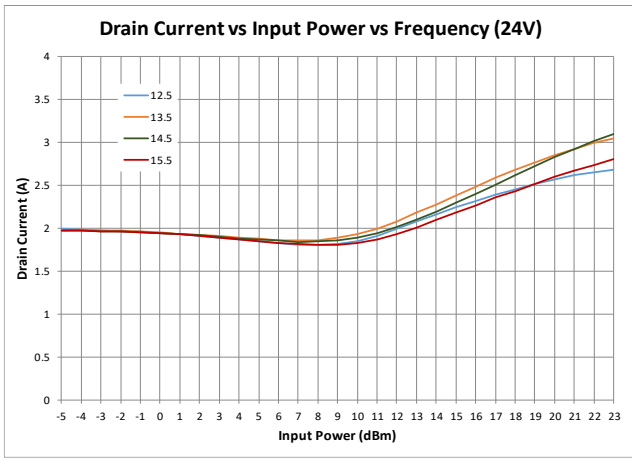
### Large Signal Performance

Test Condition:  $V_d = 28, 24 \text{ V}$ ,  $I_{dq} = 2 \text{ A}$ , Temp. =  $25 \text{ }^\circ\text{C}$ , (all data is CW in-fixture)

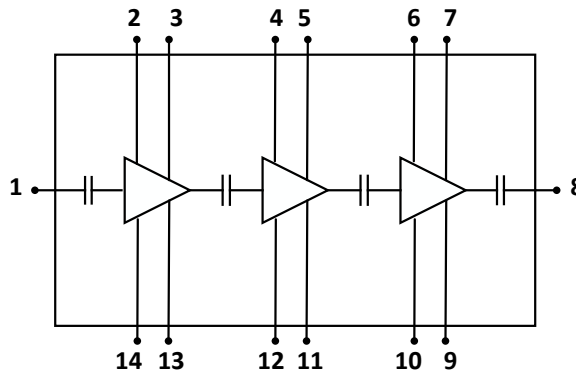


### Large Signal Performance

Test Condition:  $V_d = 28, 24 \text{ V}$ ,  $I_{dq} = 2 \text{ A}$ , Temp. =  $25 \text{ }^\circ\text{C}$ , (all data is CW in-fixture)



### Circuit Block Diagram



Pin number information detailed under Die Size and Bond Pad Information

### Die Size and Bond Pad Information

Chip Size = 4600 ±25 um x 2000 ±25 um

Chip Thickness = 100 um

Chip Backside metal is ground

RF Input/Output Pad Dimensions = 134 um x 208 um

DC Pad Dimensions:

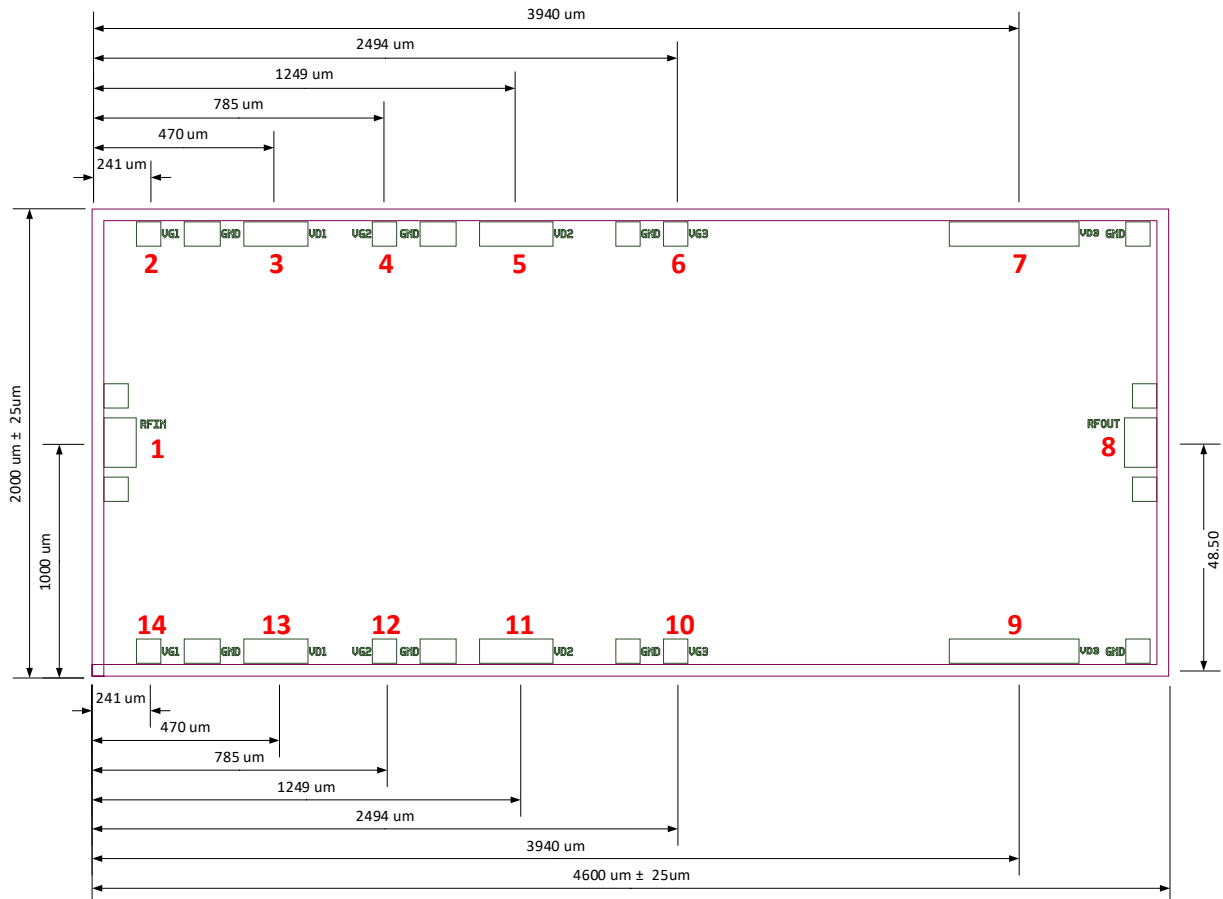
Vg1, Vg2, Vg3 = 100 um x 100 um

Vd1 = 270 um x 100 um

Vd2 = 310 um x 100 um

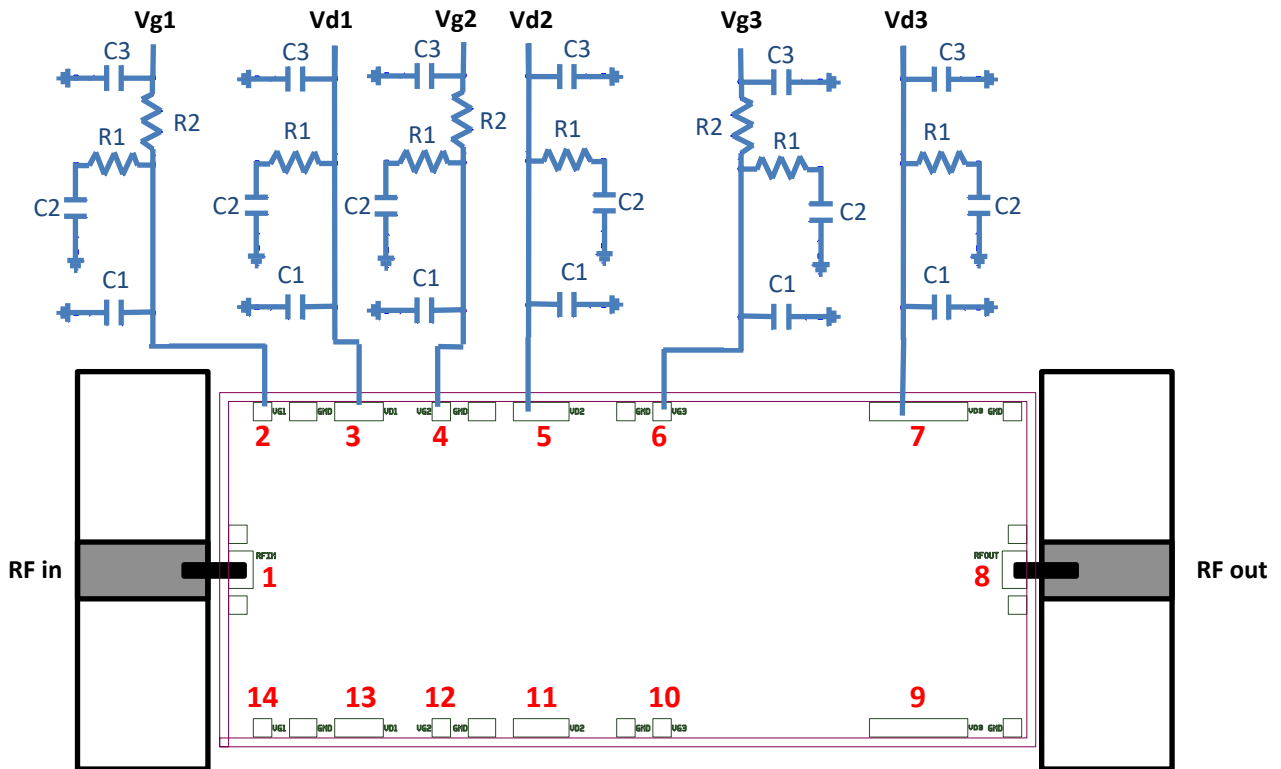
Vd3 = 550 um x 100 um

Pad Num.	Function
1	RF in
2, 14	Vg1
3, 13	Vd1
4, 12	Vg2
5, 11	Vd2
6, 10	Vg3
7, 9	Vd3
8	RF out



### Suggested Bonding Arrangement

The following diagram is a suggested bonding arrangement but other arrangements are possible. It is also possible to tie all gate voltages together as well as all drain voltages together.



### Off-Chip Component Values

Capacitor	Value
C1	100 pF
C2	0.01 $\mu$ F
C3	1 $\mu$ F

Resistor	Value
R1	10 $\Omega$
R2	100 $\Omega$

### Assembly Process

- This product has gold backside metallization and can be mounted using either a conductive epoxy or AuSn attachment.
- Nxbeam recommends the use of AuSn attachment due to the high power level of this product to ensure good thermal conductivity.
- Maximum recommended temperature during die attachment is 320 °C for 30 seconds.
- This product contains metal air bridges so caution should be taken when handling the die to avoid damage.

## Bias Information

The NPA1000-DE can be biased from either top or bottom of the chip.

### Bias-up Procedure:

- 1.) It is recommended that voltage and current limits are set on the voltage supply's prior to biasing the product.
- 2.) Ensure power supplies are properly grounded to the product test fixture.
- 3.) Apply negative gate voltage (-6 V) to ensure all devices are pinched off.
- 4.) Gradually increase the drain bias voltage to the desired bias level but not to exceed the maximum voltage of 28 V.
- 5.) Gradually increase the gate voltage while monitoring the drain current until the desired drain current is achieved.
- 6.) Apply RF signal.

### Bias-down Procedure:

- 1.) Turn off RF signal.
- 2.) Gradually decrease the gate voltage down to -6 V.
- 3.) Gradually decrease the drain voltage down to 0 V.
- 4.) Gradually increase gate voltage to 0 V.
- 5.) Turn off supply voltages

### ESD Sensitive Product



## Important Information

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